


<b>Search Notes</b>  	<b>Application/Control No.</b>  10537086	<b>Applicant(s)/Patent Under Reexamination</b>  BANIEL, AVRAHAM
	<b>Examiner</b>  Nikki H Dees	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
426	534, 611	06/26/2008	nhd

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search in eDAN	06/26/2008	nhd
EAST search history attached	06/27/2008	nhd

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner